

Special Issue

Reliability Assessment and Modeling of Optical and Semiconductor Devices

Message from the Guest Editors

This Special Issue will focus on recent developments in research in optical and semiconductor device reliability, such as reliability assessment, testing, modeling, and failure analysis, for optical and semiconductor devices. In addition, the goal of this Special Issue is to focus on cross-fertilized communication in the state of the art of reliability of optical and semiconductor devices and provide fundamental understanding of basic phenomena that affect reliability. This special issue mainly focuses on, but not limited to, the following topics:

- Reliability assessment and testing of optoelectronic semiconductor devices;
- Reliability assessment and testing of electronic semiconductor devices;
- Reliability modeling and simulation of optoelectronic semiconductor devices;
- Reliability modeling and simulation of electronic semiconductor devices;
- Reliability methodology and prediction of optoelectronic semiconductor devices;
- Reliability methodology and prediction of electronic semiconductor devices;
- Failure analysis of optoelectronic semiconductor devices;
- Failure analysis of electronic semiconductor devices.

Guest Editors

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Deadline for manuscript submissions

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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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